IEEE P1581: To Live or Let die?

Frans de Jong, Leon van de Logt, Philips Research Eindhoven, NL
leon.van.de.logt@philips.com frans.de.jong@philips.com

Abstract
Since 2001, the IEEE P1581 working group aims to provide a test standard for memories that cannot have boundary-scan. This P1581 activity focuses on test access and test circuitry. This paper elaborates on the status of the draft standard. It describes the test circuitry and an economic model for users of P1581 devices is presented. Currently, the working group is facing a lack of interest of active participants. Continuation of the P1581 standard is under discussion. An introduction to a discussion for the future of P1581 is given.

This paper was submitted under the ITC Special Board and System Test Call-for-Papers that had an extended due-date. As such, the full text of the paper was not available in time for inclusion in the general volume of the 2003 ITC Proceedings. The full text is available in *2003 ITC Proceedings—Board and System Test Track.*

Proceedings of the International Test Conference 2003 (ITC'03)
1089-3539/03 $ 17.00 © 2003 IEEE

IEEE COMPUTER SOCIETY